## ELECTRONIC DEVICES AND CIRCUITS LABORATORY

III Semester: ECE										
Course Code	Category	Hours / Week			Credits	Maximum Marks				
AEC101	Core	L	Т	Р	С	CIA	SEE	Total		
		-	-	3	2	30	70	100		
Contact Classes: Nil	Tutorial Classes: Nil	Practical Classes: 39 Total Classes: 39								

#### I. COURSE OVERVIEW:

This course provides the hands-on experience by examining the voltage-current characteristics of diodes, Bipolar Junction Transistors, Field Effect Transistors and its applications. Analyze the de- vices for measuring device characteristic parameters for designing semiconductor circuits.Extract the characteristics of semiconductor devices using multiuse simulation tool

#### **II. OBJECTIVES:**

#### The course should enable the students to:

- I The behavior and characteristics of semiconductor devices for designing thesemiconductor circuits such as amplifier and rectifiers.
- **II** Estimation of device characteristics like gain, bandwidth, input and output resistance of bipolar junction transistors and field effect transistors amplifiers to derive appropriate small-signal model analysis of basic amplifier circuits.
- III The analytical skills to model analog and digital integrated circuits at discrete and microcircuit level.

#### **III. COURSE OUTCOMES:**

#### After successful completion of the course, students should be able to:

- CO 1 Analyze the semiconductor diode characteristics for measuring the static, dynamic Analyze resistances and cut-in voltage.
- CO 2 **Construct** the pn junction diode and Zener diode characteristics for the diode Apply applications such as rectifiers and voltage regulator.
- CO 3 **Examine** the input and output characteristics of transistor (BJT and FET) Analyze configurations for determining the input output resistances.
- CO 4 **Compare BJT** and FET amplifiers for estimating the voltage gain and Current Analyze gain.
- CO 5 Calculate the intrinsic stand-off ratio of the uni junction transistor using volt Apply ampere characteristics.
- CO 6 **Determine** holding, latching current and break over voltage of silicon controlled Apply rectifier using volt ampere characteristics.

## **IV. SYLLABUS:**

## LIST OF EXPERIMENTS

## WEEK-1 ELECTRONIC WORKSHOP PRACTICE

Identification, specifications, testing of R, L, C components (Color Codes), potentiometers, switches (SPDT, DPDT and DIP), coils, gang condensers, relays, bread boards, PCBs, identification, specifications and testing of active devices, diodes, BJTs, low power JFETs, MOSFETs, power transistors, LEDs, LCDs, optoelectronic devices, SCR, UJT, DIACs.

## WEEK-2 ELECTRONIC WORKSHOP PRACTICE

# Study and operation of

a. Multimeters (Analog and Digital)

b. Function Generator				
c. Regulated Power Supplies d. Study and Operation of CRO				
WEEK-3	PN DIODE CHARACTERISTICS			
Verification of V-I characteristics of PN diode and calculate static and dynamic resistance using hardware and digital simulation.				
WEEK-4	ZENER DIODE CHARACTERISTICS AND VOLTAGE REGULATOR			
Verification of V-I characteristics of Zener diode and perform Zener diode as a Voltage regulator using hardware and digital simulation.				
WEEK-5	HALF WAVE RECTIFIER			
Verification of	half wave rectifier without and with filters using hardware and digital simulation.			
WEEK-6	FULL WAVE RECTIFIER			
Verification of Full Wave Rectifier without and with filters using hardware and digital simulation.				
WEEK-7	TRANSISTOR CB CHARACTERISTICS			
Verification of	Input and Output characteristics of CB configuration using hardware and digital simulation.			
WEEK-8	TRANSISTOR CE CHARACTERISTICS			
Verification of Input and Output Characteristics of CE configuration using hardware and digital simulation.				
WEEK-9	FREQUENCY RESPONSE OF CE AMPLIFIER			
Determine the Gain and Bandwidth of CE amplifier using hardware and digital simulation.				
WEEK-10	FREQUENCY RESPONSE OF CC AMPLIFIER			
Determine the	Gain and Bandwidth of CC amplifier using hardware and digital simulation.			
WEEK-11	UJT CHARACTERISTICS			
Verification of V-I Characteristics of UJT using hardware and digital simulation.				
WEEK-12	SCR CHARACTERISTICS			
Verification of V-I Characteristics of SCR using hardware and digital simulation.				
WEEK-13	FET CHARACTERISTICS			
Verification of V-I Characteristics of FET using digital simulation.				
WEEK-14	FREQUENCY RESPONSE OF CS AMPLIFIER			
Determine the Gain and Bandwidth of CS amplifier using digital simulation.				
WEEK-15	FREQUENCY RESPONSE OF CD AMPLIFIER			
Determine the Gain and Bandwidth of CS amplifier using digital simulation.				
Reference Books:				

- 1. J. Millman, C.C.Halkias, "Millman's Integrated Electronics", Tata McGraw Hill, 2<sup>nd</sup> Edition, 2001.
- 2. J. Millman, C.C.Halkias and Satyabrata Jit, "Millman's Electronic Devices and Circuits", Tata McGraw Hill, 2nd Edition, 1998.
- 3. Mohammad Rashid, "Electronic Devices and Circuits", Cengage learning, 1<sup>st</sup> Edition, 2014.
- 4. David A. Bell, "Electronic Devices and Circuits", Oxford University Press, 5th Edition, 2009.

#### Web References:

- 1. https://archive.org/details/ElectronicDevicesCircuits
- 2. http://www.tedpavlic.com/teaching/osu/ece327/

## **Course Home Page:**

## LIST OF EQUIPMENT REQUIRED FOR A BATCH OF 36 STUDENTS

S. No	Name of the Equipment	Range
1	Regulated Power Supply	0-30V DC
2	Cathode Ray Oscilloscope	0-20 MHz
3	Digital voltmeter	0-1V, 0-20 V
4	Digital ammeter	0-200 mA, 0-200 µA
5	Resistors	1KΩ, 100KΩ, 470 Ω, 150 Ω,10KΩ, 47K Ω,1MΩ, 2.2k Ω, 220KΩ
6	Capacitors	0.01μF, 0.01μF, 100 μF(Electrolytic) , 10μF (Electrolytic)
7	Diodes	1N4007, 4V7, 6V2.
8	Transistors	BC107, 2N2646, C106MG /XL084.
9	Semiconductor Trainer Kit	
10	Connecting Wires and Patch cords	
11	Decade resistance box	10 Ω -100k Ω
12	Decade Capacitance box	10μF-100 μF
13	Function Generator	10Hz-1M Hz
14	Digital Multimeters	0-20V/ 0-200mA/10 Ω -10k Ω
15	Bread Board	